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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : 10/696,738
Applicant : Yager et al.
Filed : October 28, 2003
Title : Wavelength Tunable Surface Plasmon Resonance Sensor
Confirmation No. : 6310
TC/A.U. : 2877
Examiner : Juan D. Valentin
Docket No. : 128-02

CERTIFICATE OF MAILING
I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as Express Mail in an envelope addressed to: Mail Stop Amendment,
Hon. Commissioner for Patents, PO Box 1450,
Alexandria VA 22313-1450 EV 529 737 387 US

15 July 04 Kay Speaker
Date: 15 July 04
Kay Speaker

INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner of Patents
Mail Stop Amendment
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

The Examiner is respectfully requested to consider the references, copies enclosed, which may qualify as prior art. For the Examiner's convenience, the references are listed on the attached Patent and Trademark Office form PTO-1449.

References listed in the PTO Form 1449 submitted herewith which do not specify the month of publication have a year of publication sufficiently earlier than the effective US filing date and any foreign priority date so that the particular month of publication is not an issue.

References known to the applicants have been listed on PTO-1449. That information is cited in a spirit of forthrightness and cooperation to enable the applicants to obtain that measure of protection for the invention to which there is entitlement. However, no representation is made that the listed art actually qualifies as prior art under the patent

statute and the mere use of PTO-1449 is not an admission that all listed references are prior art. No representation is made that applicants know of the best art.

It is believed that a fee of \$180.00 is due with the submission of this Information Disclosure Statement and a check in that amount is enclosed. If this amount submitted is incorrect, please charge any underpayment or credit any overpayment to Deposit Account No. 07-1969.

Respectfully submitted,



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Docket 128-02



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ATTY DOCKET NO. 128-02	SERIAL NO. 10/696,738	FILING DATE 10/28/03
APPLICANT Yager		GROUP 2877 Confirmation No. 6310

U.S. PATENT DOCUMENTS

Exmr. Initial		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclas s	Translation Yes/No
		WO 02/059602 A2	08/01/2002	PCT	G01N	33/543	

NON-PATENT REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

		Begley, D.L. and Seery, B.D., "Narrowband optical interference filters" (1991) <u>Free-Space laser communication technologies III</u> , SPIE Proceedings, Vol. 1417:525-536
		Berger, C. E. H., R. P. H. Kooyman, et al. (1994). "Resolution in surface plasmon microscopy." <u>Review of Scientific Instruments</u> 65 (9): 2829-2836
		Berning, Peter H., (1963) "Theory and calculations of optical thin films," <u>Physics of Thin Films</u> , G. Hass, New York, Academic Press 1:69-120
		Brockman, J. M. et al. (2000), "Surface plasmon resonance imaging measurements of ultrathin organic films." <u>Annual Reviews of Physical Chemistry</u> 51 :41-63
		de Bruijn, H. E. et al. (1992), "Choice of metal and wavelength for surface-plasmon resonance sensors: some considerations." <u>Applied Optics</u> 31 (4): 440-442
		de Bruijn, H. E. et al. (1993), "Surface plasmon resonance microscopy: improvement of the resolution by rotation of the object." <u>Applied Optics</u> 32 (13): 2426-2430
		Fu, E. et al. (June 2003), "Wavelength-tunable surface plasmon resonance microscope," <u>Rev. Sci. Instruments</u> 74 (6):3182-3184
		Hickel, W. and W. Knoll (1991), "Time and spatially resolved surface plasmon optical investigation of the photodesorption of Langmuir-Blodgett multilayer assemblies." <u>Thin Solid Films</u> 199 :367-373

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		Nelson, B.P. et al., (1999), "Near-infrared surface plasmon resonance measurements of ultrathin films. 1. Angle shift and SPR imaging experiments," <u>Anal. Chem.</u> 71 (18):3928-3934
		Rothenhäusler, B. and W. Knoll (1988), "Surface-plasmon microscopy." <u>Letters to Nature</u> 332 (14): 615-617.

EXAMINER	DATE CONSIDERED
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

12/20/89